

Experiment Device: FEI V460

Product Type	Membrane THK	Window size	Detetor	Sample		Resolution		EDS	Limitation	Note	
				High atomic number (>14)	Low atomic number (<14)	High atomic number (>14)	Low atomic number (<14)				
Standard	50nm	150 x 150um	SE	O	X	150±30 nm	X	O	HF/hot H ₃ PO ₄	lower demand/ cost reduction	
			BSE	O	X	100±30 nm	X	O			
High magnification	20nm	20 x 20um	SE	O	O	70±20 nm	100±20 nm	X		X	high image quality/ Recommendation
			BSE	O	O	30±20 nm	50±20 nm	X			
large window	30nm	250 x 250um	SE	O	O	80±20 nm	140±20 nm	O		O	high risk of rupture
			BSE	O	O	40±20 nm	70±20 nm	O			

※Sample example

High atomic number : paste(Au, Ni,Cu, Silver) 、 slurry(TiO₂, CeO₂, BaTiO₃...)

Low atomic number : Slurry(SiO₂, Al₂O₃, Graphite...) 、 Carbon Black Resist